

**(+)-3-[(4*S*,5*S*)-5-[1,1-dimethyl-2-(phenylthio)ethyl]-2,2-dimethyl-1,3-dioxolan-4-yl]prop-2-yn-1-ol**

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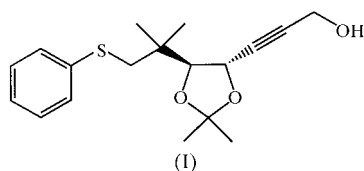
Received 28 February 2000  
Accepted 2 March 2000

Data validation number: IUC0000057

The absolute configuration was determined for the title compound, (+)-C<sub>18</sub>H<sub>24</sub>O<sub>3</sub>S, (I), which was prepared in a synthetic study on the natural products, bryostatins.

**Comment**

A synthetic study on bryostatin 3 has been reported (Obitsu *et al.*, 1998).



**Experimental**

The title optically active compound was prepared by the authors in a synthetic study on bryostatins (Ohmori *et al.*, 2000). The angle of rotation [ $\alpha$ ]<sub>D</sub><sup>21</sup> is +20.9° (*c* 1.0, CHCl<sub>3</sub>). Crystals were grown from a hexane/ethyl acetate solution.

*Crystal data*

C<sub>18</sub>H<sub>24</sub>O<sub>3</sub>S  
*M<sub>r</sub>* = 320.45  
Orthorhombic, *P*2<sub>1</sub>2<sub>1</sub>2<sub>1</sub>  
*a* = 8.760 (2) Å  
*b* = 32.090 (2) Å  
*c* = 6.269 (2) Å  
*V* = 1762.3 (6) Å<sup>3</sup>  
*Z* = 4  
*D<sub>x</sub>* = 1.208 Mg m<sup>-3</sup>

Cu *K*α radiation  
Cell parameters from 25 reflections  
 $\theta$  = 29.1–30.0°  
 $\mu$  = 1.706 mm<sup>-1</sup>  
*T* = 248 (1) K  
Prism, colourless  
0.5 × 0.5 × 0.3 mm

Rigaku AFC-7R diffractometer  
 $\theta$ –2 $\theta$  scans

Absorption correction: by integration (Coppens *et al.*, 1965)  
*T*<sub>min</sub> = 0.476, *T*<sub>max</sub> = 0.636  
2633 measured reflections

*Data collection*

2147 independent reflections  
2055 reflections with *I* > 2σ(*I*)  
*R*<sub>int</sub> = 0.036  
 $\theta$ <sub>max</sub> = 75°  
*h* = –11 → 5

*k* = –20 → 40  
*l* = –4 → 8  
3 standard reflections every 150 reflections  
intensity decay: none

*Refinement*

Refinement on *F*<sup>2</sup>  
*R*(*F*) = 0.040  
*wR*(*F*<sup>2</sup>) = 0.108  
*S* = 1.08  
2147 reflections  
203 parameters  
H atoms treated by a mixture of independent and constrained refinement  
*w* = 1/[σ<sup>2</sup>(*F*<sub>o</sub><sup>2</sup>) + (0.0524*P*)<sup>2</sup> + 0.8338*P*]  
where *P* = (*F*<sub>o</sub><sup>2</sup> + 2*F*<sub>c</sub><sup>2</sup>)/3

(Δ/σ)<sub>max</sub> = 0.001  
Δρ<sub>max</sub> = 0.43 e Å<sup>-3</sup>  
Δρ<sub>min</sub> = –0.41 e Å<sup>-3</sup>  
Extinction correction: *SHELXL97* (Sheldrick, 1997)  
Extinction coefficient: 0.0101 (6)  
Absolute structure: Flack (1983), 163 Friedel pairs  
Flack parameter = 0.03 (3)

**Table 1**

Selected geometric parameters (Å, °).

S1–C5	1.762 (3)	C17–C18	1.188 (4)
S1–C11	1.813 (3)	C18–C19	1.465 (5)
C16–C17	1.465 (4)		
C5–S1–C11	103.1 (1)	C17–C18–C19	178.9 (3)
C16–C17–C18	177.7 (3)		

**Table 2**

Hydrogen-bonding geometry (Å, °).

<i>D</i> –H... <i>A</i>	<i>D</i> –H	H... <i>A</i>	<i>D</i> ... <i>A</i>	<i>D</i> –H... <i>A</i>
O4–H4...O3 <sup>i</sup>	0.98 (3)	1.86 (3)	2.816 (3)	164 (3)

Symmetry code: (i) *x* – ½, ½ – *y*, –*z*.

X-ray intensities were measured for –*h*+*k*+*l* ( $\theta$  < 75°), +*h*+*k*–*l* ( $\theta$  < 30°) and +*h*–*k*–*l* ( $\theta$  < 30°). There were 163 Friedel pairs, which were not averaged. The completeness of symmetry unique reflections ( $\theta$  < 75°) was 93.3%, which was due to the blind region of the low-temperature apparatus. The hydroxyl H atom was located from a difference synthesis. Their positional parameters were refined with restraint of O–H = 0.98 Å (s.u. 0.01 Å) with *U*<sub>iso</sub>(H) = 1.2*U*<sub>eq</sub>(parent atom). The other H-atom positional parameters were calculated geometrically and fixed with *U*<sub>iso</sub>(H) = 1.2*U*<sub>eq</sub>(parent atom). The absolute structure was determined based on a Flack parameter value of 0.03 (3).

Data collection: *MSC/AFC Diffractometer Control Software* (Molecular Structure Corporation, 1993); cell refinement: *MSC/AFC Diffractometer Control Software*; data reduction: *TEXSAN* (Molecular Structure Corporation, 1999); program(s) used to solve structure: *SIR92* (Altomare *et al.*, 1994); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); software used to prepare material for publication: *TEXSAN*.

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